


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/052,111	SCHRADER ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Annan Q. Shang	2623	

SEARCHED			
Class	Subclass	Date	Examiner
725	87-104	9/29/2006	A.S

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR